#### U.S. PATENT DOCUMENTS

EXAMINER INITIALS	REF. NO.	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	LOCATION WHERE RELEVANT PASSAGES OR FIGURES APPEAR

#### FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	REF. NO.	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	LOCATION WHERE RELEVANT PASSAGES OR FIGURES APPEAR	Т
KIM	1*	JP 11-302020 A1	11/2/1999	Yamada et al.		Abstract Only
· KM	2	CN 1189143 A	7/29/1998	Bowden et al.		
JUM	3	WO 96/40590 A1	12/19/1996	Bowden et al.		

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER REF	

\*Cited in U.S. Serial No. 09/707,100, now Patent No. 6,555,026

EXAMINER W	DATE CONSIDERED	may 26	w 4
*EXAMINER: Initial if citation considered, whether or not citation is in conform conformance and not considered. Include copy of this form with next communic	ance with MPEP 609; ation to applicant.	<i>J 7</i>	7

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# PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Sheet 1 of 2

ATTORNEY DOCKET No.	SERIAL NO.
4858-000021/CPE	09/974,043
APPLICANT	
Jeremy Barker, et al.	
FILING DATE	GROUP
10/09/2001	

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ ∫Subclass	(If appropriate) Filing Date
1.	Knw	4,215,188	7/29/80	Saathoff, et al.		
2.	1c nw	4,279,972	7/21/81	Moses		
3.	10 pw	4,465,747	8/14/84	Evans		
4.	KIW	5,168,019	12/1/92	Sugeno		
5.	/CHW	5,192,629	3/9/93	Guyomard, et al.		
6.	10ml	5,399,447	3/21/95	Chaloner-Gill, et al.	\	\ <del>  </del>
7.	1( KW	5,419,985	5/30/95	Koksbang		\
8.	tim	5,427,875	6/27/95	Yamamoto, et al.		_\
9.	1 m	5,435,054	7/25/95	Tonder, et al.		
10.	km	5,449,577	09/12/95	Dahn, et al.		$\perp \perp$
11.	10 m	5,463,179	10/31/95	Chaloner-Gill, et al.		
12.	knw	5,474,858	12/12/95	Merritt		
13.	2 gw	5,482,795	1/9/96	Chaloner-Gill		$\perp$
14.	KM	5,683,835	11/4/97	Bruce		
15.	(m)	5,693,307	12/02/97	Borden, et al.		
16.	10 rw	5,702,679	12/30/97	Sheargold, et al.		
17.	rw	5,733,685	03/31/98	Wang		
18.	2 mil	5,753,202	05/19/98	Wang, et al.		
19.	(cm)	5,783,328	07/21/98	Wang		
20.	lun	5,939,043	08/17/99	Yahagi		

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	<del></del>	<del>\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\</del>	<del></del>	<sup>-7</sup> 1	/	/	<i>-</i>

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(Use several sheets if necessary)

Sheet 2 of 2

ATTORNEY DOCKET No.	SERIAL NO.
4858-000021/CPE	09/974,043
APPLICANT	
Jeremy Barker, et al.	
FILING DATE	GROUP
10/09/2001	

FORE	IGN PATEN	T DOCUMENTS				
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
1.	1 mm	JP 07 235 297	09/05/95	Japan		Abstract
2.	Km	JP 08 321 326	12/03/96	Japan		Abstract
3.	Kent	JP 06 333 598	12/02/94	Japan		Abstract
4.	DWV	JP 59 081 870	05/11/84	Japan		Abstract
5.	1(m	JP 61 165 961	07/26/86	Japan		Abstract
6.	CW	JP 04 363 865	12/16/92	Japan		Abstract
7.	Chr	JP 07 262 984	10/23/01	Japan		X
8.	NW	WO 01 13443 A2	02/22/01	PCT		
9.	NOW	WO 92 20112	11/12/92	PCT		Abstract
10.	OW	WO 00 49668	08/24/00	PCT		<u> </u>

OTHE	OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)				
Ref. Desig.	Examiner's Initials				
1.	(m)	Amatucci, et al., Solid State Ionics, vol. 104, pp. 13-25 (1997)*			
2.	m	Herlem, et al., Electrochimica Acta, vol. 41, no. 17, pp. 2753-2760 (1996)			

Examiner:

Date Considered:

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